M JJMICROELECTRONICS

40V, 223A, 1.4m Ω N-channel Power SGT MOSFET

JMSH0401MGQ

Features

- Ultra-low ON-resistance, R_{DS(ON)}
- Low Gate Charge
- 100% UIS Tested
- 100% ΔVds Tested
- Halogen-free; RoHS-compliant
- AEC-Q101 Qualified

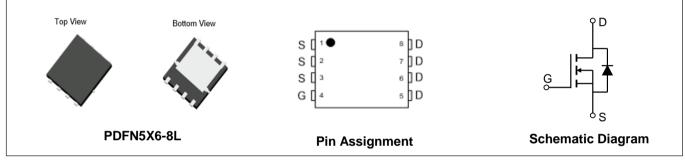
Applications

- Load Switch
- PWM Application
- General Automotive Application

Product Summary

Parameters	Value	Unit
V _{DSS}	40	V
V _{GS(th)_Typ}	2.7	V
I _D (@V _{GS} =10V)	223	A
R _{DS(ON)_Typ} (@V _{GS} =10V	1.4	mΩ





Ordering Information

Device	Device Marking MSL		Form Package		Reel(pcs)	Per Carton (pcs)
JMSH0401MGQ-13	SH0401MQ	1	Tape&Reel	PDFN5x6-8L	5000	50000

Absolute Maximum Ratings (@ $T_c = 25^{\circ}C$ unless otherwise specified)

Symbol	Parameter		Value	Unit	
V _{DS}	Drain-to-Source Voltage		40	V	
V _{GS}	Gate-to-Source Voltage		±20	V	
1-	Continuous Drain Current	$T_C = 25^{\circ}C$	223	А	
Ι _D	Continuous Dialit Current	$T_{\rm C} = 100^{\circ}{\rm C}$	158	~	
I _{DM}	Pulsed Drain Current ⁽¹⁾		Refer to Fig.4	A	
E _{AS}	Single Pulsed Avalanche Energy ⁽²⁾		459	mJ	
P _D		$T_{C} = 25^{\circ}C$	157	w	
۰D		$T_{c} = 100^{\circ}C$	78		
T _J , T _{STG}	Junction & Storage Temperature Range		-55 to 175	°C	

Thermal Characteristics

Symbol	Parameter	Мах	Unit
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient ⁽³⁾	42	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction to Case	1.0	0/10

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Off Cha	aracteristics			<u>I</u>	1	
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0V$	40	-	-	V
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 32V, V_{GS} = 0V$	-	-	1.0	μA
I _{GSS}	Gate-Body Leakage Current	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	±100	nA
On Cha	racteristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1.9	2.7	3.5	V
R _{DS(ON)}	Static Drain-Source ON-Resistance ⁽⁴⁾	$V_{GS} = 10V, I_{D} = 20A$	-	1.4	1.7	mΩ
Dynami	ic Characteristics					
R_{g}	Gate Resistance	f = 1MHz	-	0.9	-	Ω
C _{iss}	Input Capacitance		2589	3625	4893	pF
C _{oss}	Output Capacitance	$V_{GS} = 0V, V_{DS} = 20V,$ f = 1MHz	1413	1979	2671	pF
C _{rss}	Reverse Transfer Capacitance		113	158	213	pF
Qg	Total Gate Charge		42	59	80	nC
Q_{gs}	Gate Source Charge	$V_{GS} = 0 \text{ to } 10V$ $V_{DS} = 20V, I_D = 20A$	11	15	21	nC
Q_{gd}	Gate Drain("Miller") Charge	VDS = 200, 10 = 207	12	16	22	nC
Switchi	ing Characteristics					
t _{d(on)}	Turn-On DelayTime		-	16	-	ns
tr	Turn-On Rise Time	V _{GS} = 10V, V _{DD} = 20V	-	29	-	ns
t _{d(off)}	Turn-Off DelayTime	I_D = 20A, R_{GEN} = 3 Ω	-	35	-	ns
t _f	Turn-Off Fall Time		-	13	-	ns
Body D	iode Characteristics			D	1	
I _S	Maximum Continuous Body Diode Forward Current		-	-	223	А
I _{SM}	Maximum Pulsed Body Diode Forward Current		-	-	891	A
V_{SD}	Body Diode Forward Voltage	$V_{GS} = 0V, I_{S} = 20A$	-		1.2	V
trr	Body Diode Reverse Recovery Time	L = 20.4 di/dt = 100.4/via	37	52	70	ns
Qrr	Body Diode Reverse Recovery Charge	I _F = 20A, di/dt = 100A/us	-	66	-	nC

Electrical Characteristics (T_J = 25°C unless otherwise specified)

Notes:

1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.

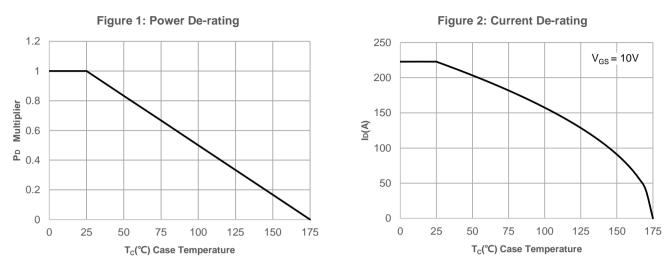
2. E_{AS} condition: Starting T_J =25C, V_{DD} =20V, V_{GS} =10V, R_G =250hm, L=3mH, I_{AS} =17.5A, V_{DD} =0V during time in avalanche.

3. $R_{\theta JA}$ is measured with the device mounted on a 1inch 2 pad of 2oz copper FR4 PCB.

4. Pulse Test: Pulse Width \leq 300µs, Duty Cycle \leq 0.5%.

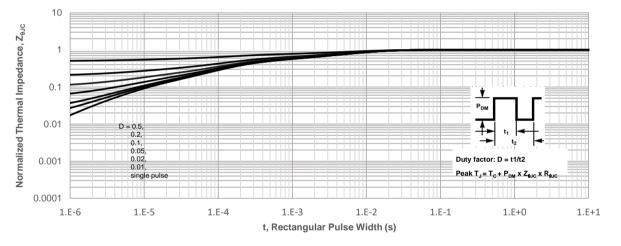




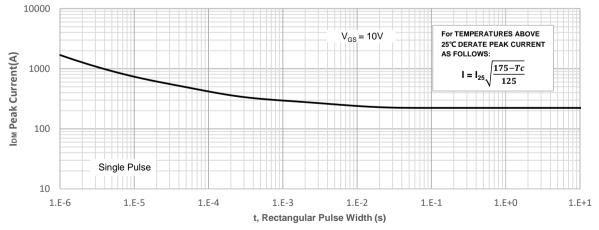


Typical Performance Characteristics

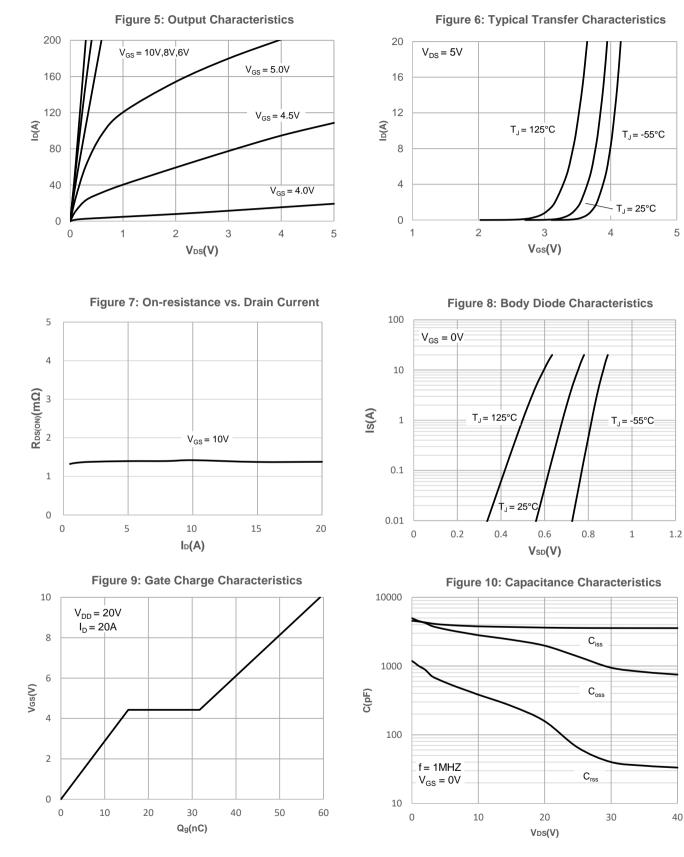








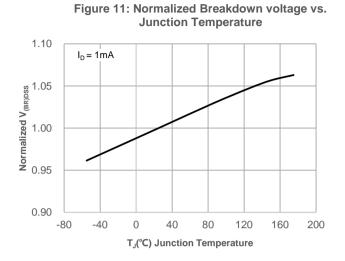




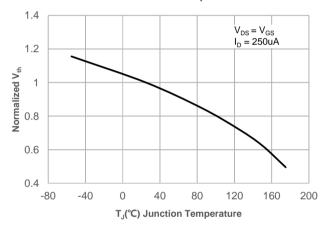
Typical Performance Characteristics

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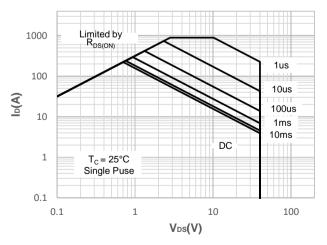


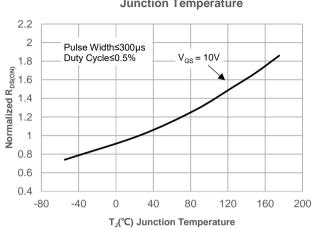












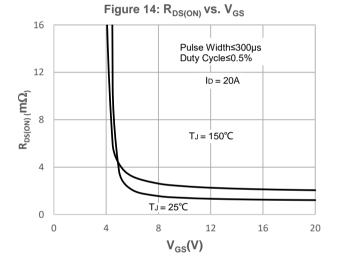


Figure 12: Normalized on Resistance vs. Junction Temperature

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Test Circuit

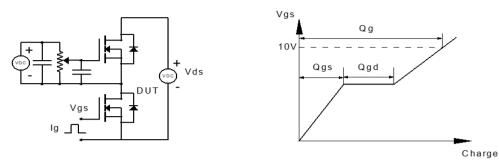


Figure 1: Gate Charge Test Circuit & Waveform

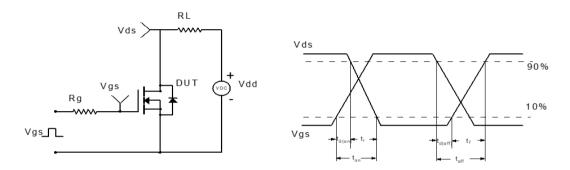


Figure 2: Resistive Switching Test Circuit & Waveform

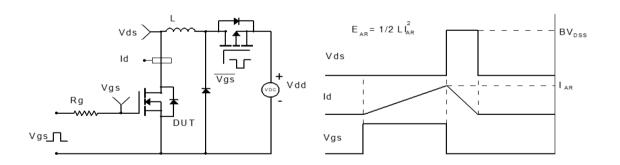


Figure 3: Unclamped Inductive Switching Test Circuit& Waveform

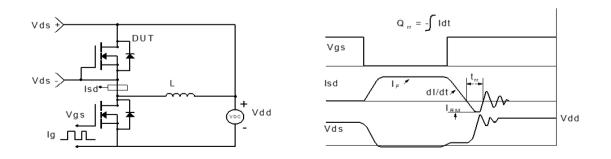
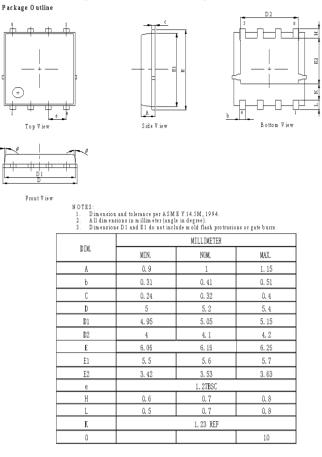


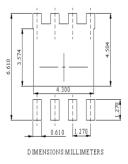
Figure 4: Diode Recovery Test Circuit & Waveform



Package Mechanical Data(PDFN5X6-8L)



Recommended Soldering Footprint



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